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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/690,399	WILLIFORD, ETHAN	
Examiner	Art Unit	
Wai-Sing Louie	2814	

SEARCHED					
Class	Subclass	Date	Examiner		
257	345,402,4 03	3/30/2005	WSL		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
257/391,392 {	2,402,403,40 3	6/7/2006	WSL	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
transistor, MOSFET, gate aperture, channel implant, angle implant, diffusion	3/30/2005	WSL
FET, TFT, gate, hole, aperture, threshold voltage adjustment, channel implant	6/7/2005	WSL
E29.049 to E29.067, E29.237 to E29.299	4/6/2007	WSL
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